

**Notice of References Cited**

Application/Control No.

09/650,218

Applicant(s)/Patent Under

Reexamination

AVERY ET AL.

Examiner

Shin-Hon Chen

Art Unit

2131

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,496,595	12-2002	Puchek et al.	382/124
	B	US-6,353,853	03-2002	Gravlin, Keith Robert	709/219
	C	US-2002/0029349	03-2002	DAIGNEAULT et al.	713/200
	D	US-5,903,225	05-1999	Schmitt et al.	340/5.25
	E	US-6,160,903	12-2000	Hamid et al.	382/115
	F	US-6,281,790	08-2001	Kimmel et al.	340/506
	G	US-4,689,610	08-1987	Dietrich, William V.	340/515
	H	US-5,541,585	07-1996	Duhame et al.	340/5.62
	I	US-6,389,454	05-2002	Ralston et al.	709/204
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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